

M5M5V416BTP

4194304-BIT (262144-WORD BY 16-BIT) CMOS STATIC RAM

DESCRIPTION

The M5M5V416B is a family of low voltage 4-Mbit static RAMs organized as 262,144-words by 16-bit, fabricated by Mitsubishi's high-performance 0.25μm CMOS technology.

The M5M5V416B is suitable for memory applications where a simple interfacing, battery operating and battery backup are the important design objectives.

M5M5V416BTP,RT are packaged in a 44-pin 400mil thin small outline package. M5M5V416BTP (normal lead bend type package), M5M5V416BRT (reverse lead bend type package), both types are very easy to design a printed circuit board.

From the point of operating temperature, the family is divided into three versions; "Standard", "W-version", and "I-version". Those are summarized in the part name table below.

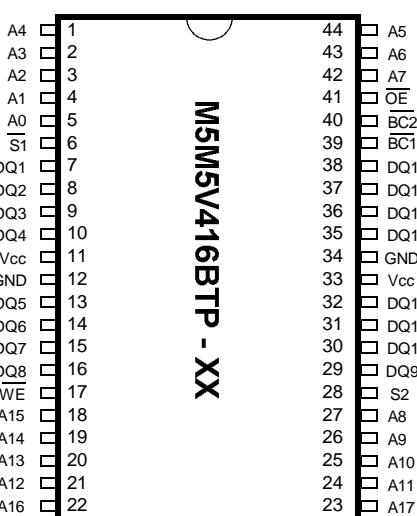
FEATURES

- Single +2.7~+3.6V power supply
- Small stand-by current: 0.3μA(3V,typ.)
- No clocks, No refresh
- Data retention supply voltage=2.0V to 3.6V
- All inputs and outputs are TTL compatible.
- Easy memory expansion by S1, S2, BC1 and BC2
- Common Data I/O
- Three-state outputs: OR-tie capability
- OE prevents data contention in the I/O bus
- Process technology: 0.25μm CMOS
- Package: 44 pin 400mil TSOP (II)

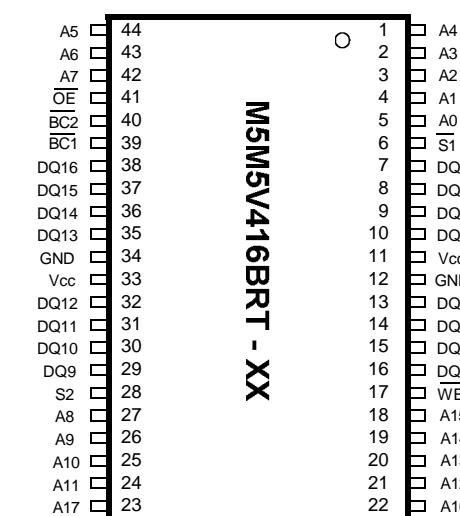
Version, Operating temperature	Part name	Power Supply	Access time max.	Stand-by current Icc(PD), Vcc=3.0V						Active current Icc1 (3.0V, typ.)	
				typical *		Ratings (max.)					
				25°C	40°C	25°C	40°C	70°C	85°C		
Standard 0 ~ +70°C	M5M5V416BTP,RT -70L	2.7 ~ 3.6V	70ns	---	---	---	---	30μA	---	50mA (10MHz) 7mA (1MHz)	
	M5M5V416BTP,RT -85L		85ns	---	---	---	---	---	---		
	M5M5V416BTP,RT -70H	2.7 ~ 3.6V	70ns	0.3μA	1μA	1μA	3μA	15μA	---		
	M5M5V416BTP,RT -85H		85ns	---	---	---	---	---	---		
W-version -20 ~ +85°C	M5M5V416BTP,RT -70LW	2.7 ~ 3.6V	70ns	---	---	---	---	30μA	60μA	50mA (10MHz) 7mA (1MHz)	
	M5M5V416BTP,RT -85LW		85ns	---	---	---	---	---	60μA		
	M5M5V416BTP,RT -70HW	2.7 ~ 3.6V	70ns	0.3μA	1μA	1μA	3μA	15μA	30μA		
	M5M5V416BTP,RT -85HW		85ns	---	---	---	---	---	30μA		
I-version -40 ~ +85°C	M5M5V416BTP,RT -70LI	2.7 ~ 3.6V	70ns	---	---	---	---	30μA	60μA	50mA (10MHz) 7mA (1MHz)	
	M5M5V416BTP,RT -85LI		85ns	---	---	---	---	---	60μA		
	M5M5V416BTP,RT -70HI	2.7 ~ 3.6V	70ns	0.3μA	1μA	1μA	3μA	15μA	30μA		
	M5M5V416BTP,RT -85HI		85ns	---	---	---	---	---	30μA		

* "typical" parameter is sampled, not 100% tested.

PIN CONFIGURATION



44P3W-H



44P3W-J

Pin	Function
A0 ~ A17	Address input
DQ1 ~ DQ16	Data input / output
S1	Chip select input 1
S2	Chip select input 2
W	Write control input
OE	Output enable input
BC1	Lower Byte (DQ1 ~ 8)
BC2	Upper Byte (DQ9 ~ 16)
Vcc	Power supply
GND	Ground supply

Outline: 44P3W-H/J

NC: No Connection

M5M5V416BTP

4194304-BIT (262144-WORD BY 16-BIT) CMOS STATIC RAM

FUNCTION

The M5M5V416BTP,RT are organized as 262,144-words by 16-bit. These devices operate on a single +2.7~3.6V power supply, and are directly TTL compatible to both input and output. Its fully static circuit needs no clocks and no refresh, and makes it useful.

The operation mode are determined by a combination of the device control inputs BC1 , BC2 , S1, S2 , W and OE. Each mode is summarized in the function table.

A write operation is executed whenever the low level W overlaps with the low level BC1 and/or BC2 and the low level S1 and the high level S2. The address(A0~A17) must be set up before the write cycle and must be stable during the entire cycle.

A read operation is executed by setting W at a high level and OE at a low level while BC1 and/or BC2 and S1 and S2 are in an active state(S1=L,S2=H).

When setting BC1 at the high level and other pins are in an active stage , upper-byte are in a selectable mode in which both reading and writing are enabled, and lower-byte are in a non-selectable mode. And when setting BC2 at a high level and other pins are in an active stage, lower-byte are in a selectable mode and upper-byte are in a non-selectable mode.

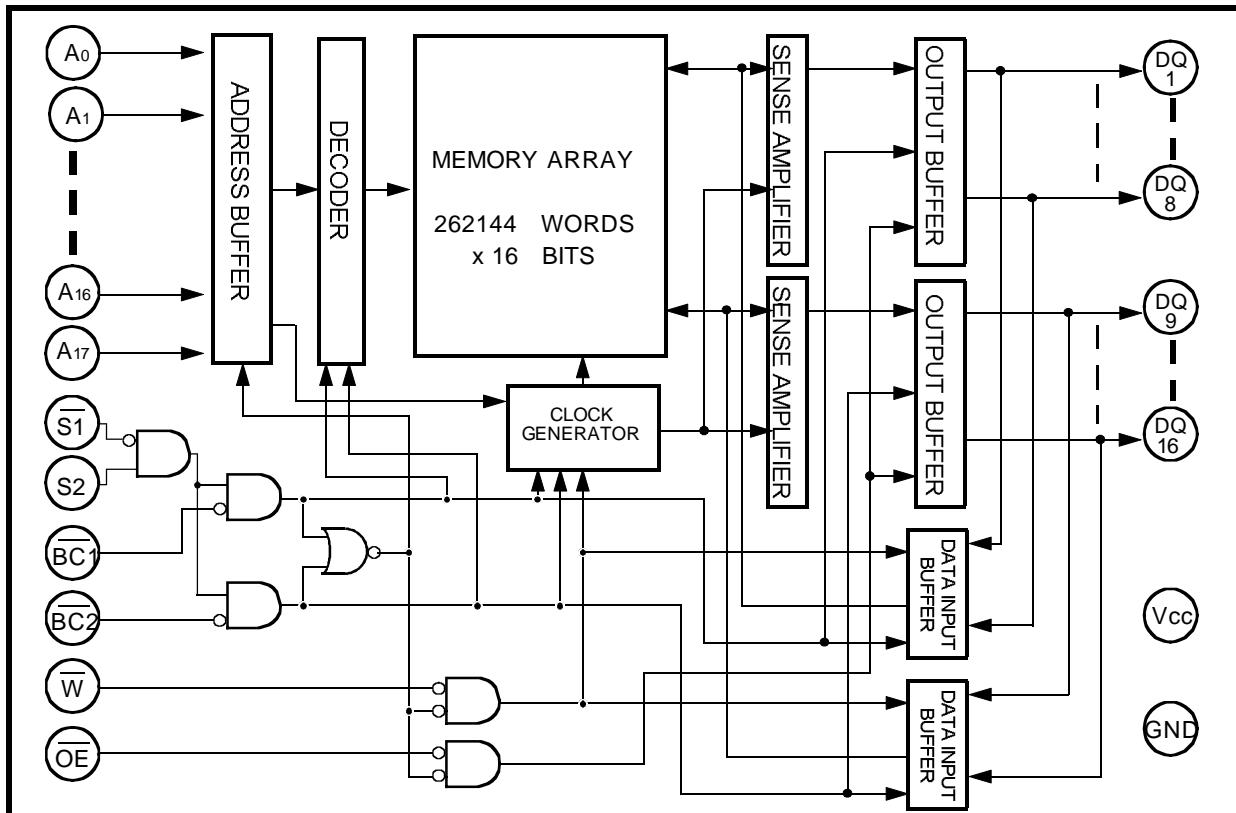
When setting BC1 and BC2 at a high level or S1 at a high level or S2 at a low level, the chips are in a non-selectable mode in which both reading and writing are disabled. In this mode, the output stage is in a high-impedance state, allowing OR-tie with other chips and memory expansion by BC1, BC2 and S1, S2.

The power supply current is reduced as low as 0.3 μ A(25°C, typical), and the memory data can be held at +2V power supply, enabling battery back-up operation during power failure or power-down operation in the non-selected mode.

FUNCTION TABLE

S1	S2	BC1	BC2	W	OE	Mode	DQ1~8	DQ9~16	Icc
H	L	X	X	X	X	Non selection	High-Z	High-Z	Standby
L	L	X	X	X	X	Non selection	High-Z	High-Z	Standby
H	H	X	X	X	X	Non selection	High-Z	High-Z	Standby
X	X	H	H	X	X	Non selection	High-Z	High-Z	Standby
L	H	L	H	L	X	Write	Din	High-Z	Active
L	H	L	H	H	L	Read	Dout	High-Z	Active
L	H	L	H	H	H		High-Z	High-Z	Active
L	H	H	L	L	X	Write	High-Z	Din	Active
L	H	H	L	H	L	Read	High-Z	Dout	Active
L	H	H	L	H	H		High-Z	High-Z	Active
L	H	L	L	L	X	Write	Din	Din	Active
L	H	L	L	H	L	Read	Dout	Dout	Active
L	H	L	L	H	H		High-Z	High-Z	Active

BLOCK DIAGRAM



M5M5V416BTP

4194304-BIT (262144-WORD BY 16-BIT) CMOS STATIC RAM**ABSOLUTE MAXIMUM RATINGS**

Symbol	Parameter	Conditions	Ratings	Units
V _{cc}	Supply voltage	With respect to GND	-0.5* ~ +4.6	V
V _I	Input voltage	With respect to GND	-0.5* ~ V _{cc} + 0.5	
V _O	Output voltage	With respect to GND	0 ~ V _{cc}	
P _d	Power dissipation	T _a =25°C	700	mW
T _a	Operating temperature	Standard (-L, -H)	0 ~ +70	°C
		W-version (-LW, -HW)	-20 ~ +85	
		I-version (-LI, -HI)	-40 ~ +85	
T _{stg}	Storage temperature		-65 ~ +150	°C

* -3.0V in case of AC (Pulse width \leq 30ns)**DC ELECTRICAL CHARACTERISTICS**(V_{cc}=2.7 ~ 3.6V, unless otherwise noted)

Symbol	Parameter	Conditions	Limits			Units	
			Min	Typ	Max		
V _{IH}	High-level input voltage		2.2		V _{cc} +0.3V	V	
V _{IL}	Low-level input voltage		-0.3 *		0.6		
V _{OH1}	High-level output voltage 1	I _{OH} = -0.5mA	2.4				
V _{OH2}	High-level output voltage 2	I _{OH} = -0.05mA		V _{cc} -0.5V			
V _{OL}	Low-level output voltage	I _{OL} =2mA			0.4		
I _I	Input leakage current	V _I =0 ~ V _{cc}			\pm 1	μ A	
I _O	Output leakage current	BC1 and BC2=V _{IH} or S ₁ =V _{IH} or S ₂ =V _{IH} or \overline{OE} =V _{IH} , V _I /O=0 ~ V _{cc}			\pm 1		
I _{CC1}	Active supply current (AC,MOS level)	BC1 and BC2 \leq 0.2V, S ₁ \leq 0.2V, S ₂ \geq V _{cc} -0.2V other inputs \leq 0.2V or \geq V _{cc} -0.2V Output - open (duty 100%)	f = 10MHz	-	50	70	mA
			f = 1MHz	-	7	15	
I _{CC2}	Active supply current (AC,TTL level)	BC1 and BC2=V _{IL} , S ₁ =V _{IL} , S ₂ =V _{IH} other pins =V _{IH} or V _{IL} Output - open (duty 100%)	f = 10MHz	-	50	70	
			f = 1MHz	-	7	15	
I _{CC3}	Stand by supply current (AC,MOS level)	< 1 > S ₁ \geq V _{cc} - 0.2V, other inputs = 0 ~ V _{cc} < 2 > S ₂ \leq 0.2V, other inputs = 0 ~ V _{cc} < 3 > BC1 and BC2 \geq V _{cc} - 0.2V S ₁ \leq 0.2V, S ₂ \geq V _{cc} - 0.2V Other inputs=0~V _{cc}	-LW, -LI	+85°C	-	80	μ A
			-L, -LW, -LI	+70°C	-	40	
			-HW, -HI	+85°C	-	40	
			-H, -HW, -HI	+70°C	-	20	
				+40°C	-	1	
			-H	0 ~ +25°C	-	0.3	
			-HW	-20 ~ +25°C	-	0.3	
			-HI	-40 ~ +25°C	-	0.3	
I _{CC4}	Stand by supply current (AC,TTL level)	BC1 and BC2=V _{IH} or S ₁ =V _{IH} or S ₂ =V _{IL} Other inputs= 0 ~ V _{cc}		-	-	0.5	mA

Note 1: Direction for current flowing into IC is indicated as positive (no mark)

* -3.0V in case of AC (Pulse width \leq 30ns)Note 2: Typical value is for V_{cc}=3.0V and T_a=25°C**CAPACITANCE**(V_{cc}=2.7 ~ 3.6V, unless otherwise noted)

Symbol	Parameter	Conditions	Limits			Units
			Min	Typ	Max	
C _I	Input capacitance	V _I =GND, V _I =25mVrms, f=1MHz			10	pF
C _O	Output capacitance	V _O =GND, V _O =25mVrms, f=1MHz			10	

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4194304-BIT (262144-WORD BY 16-BIT) CMOS STATIC RAM

AC ELECTRICAL CHARACTERISTICS

($V_{CC}=2.7 \sim 3.6V$, unless otherwise noted)

(1) TEST CONDITIONS

Supply voltage	2.7V~3.6V
Input pulse	$V_{IH}=2.4V, V_{IL}=0.4V$
Input rise time and fall time	5ns
Reference level	$V_{OH}=V_{OL}=1.5V$ Transition is measured $\pm 500mV$ from steady state voltage.(for t_{en}, t_{dis})
Output loads	Fig.1, CL=30pF CL=5pF (for ten,tdis)

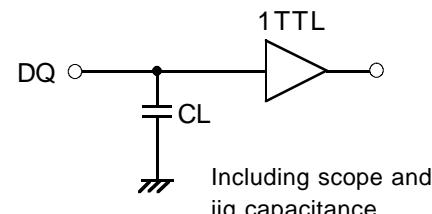


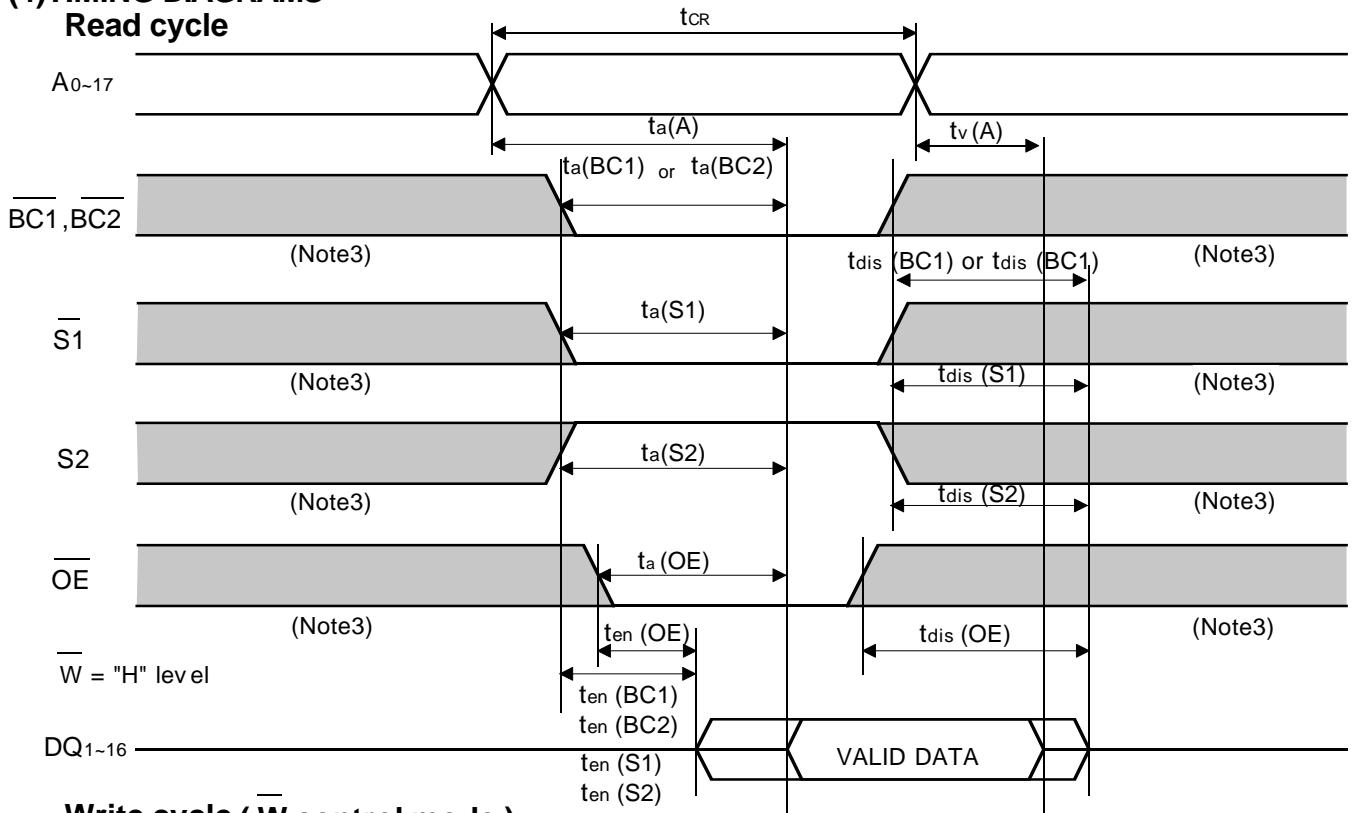
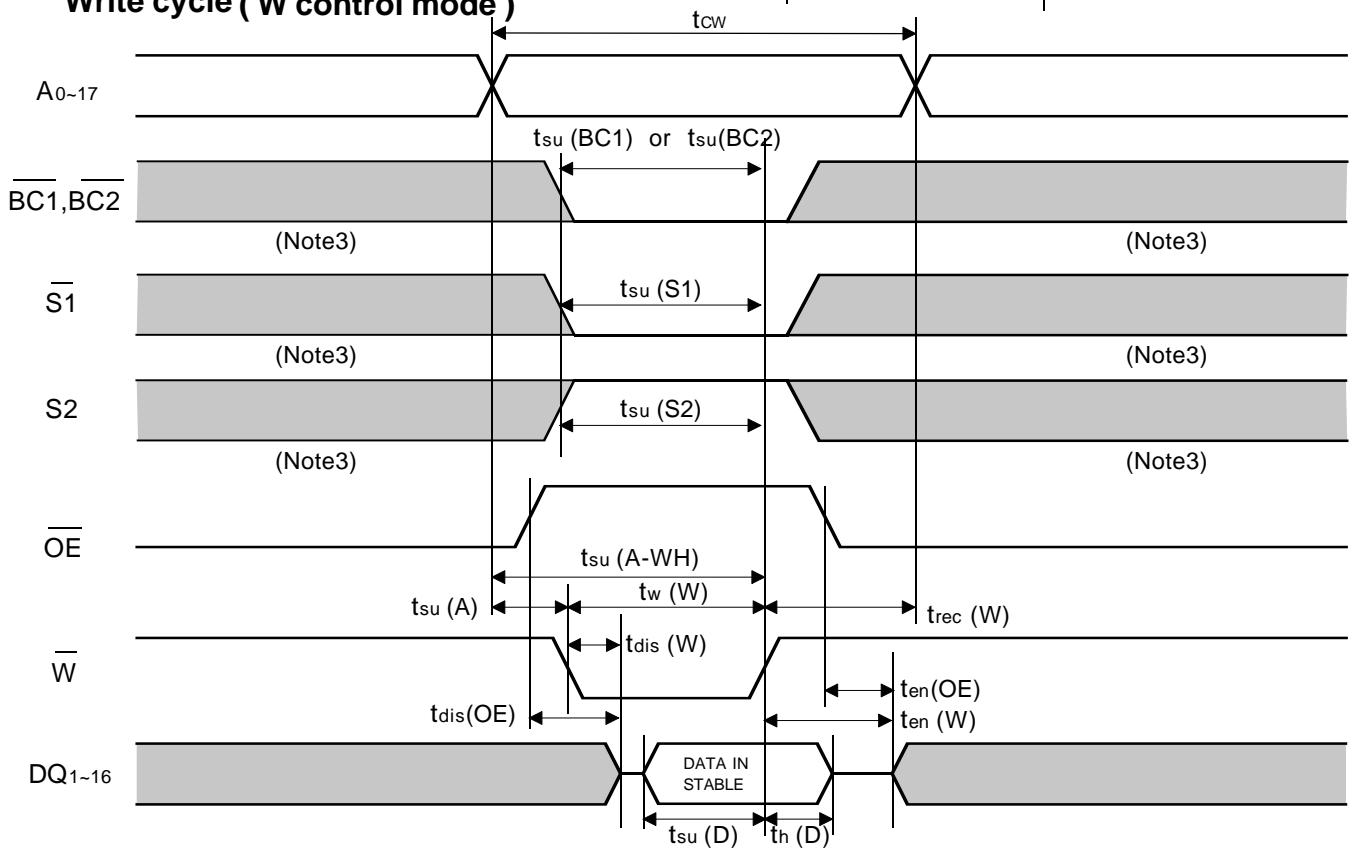
Fig.1 Output load

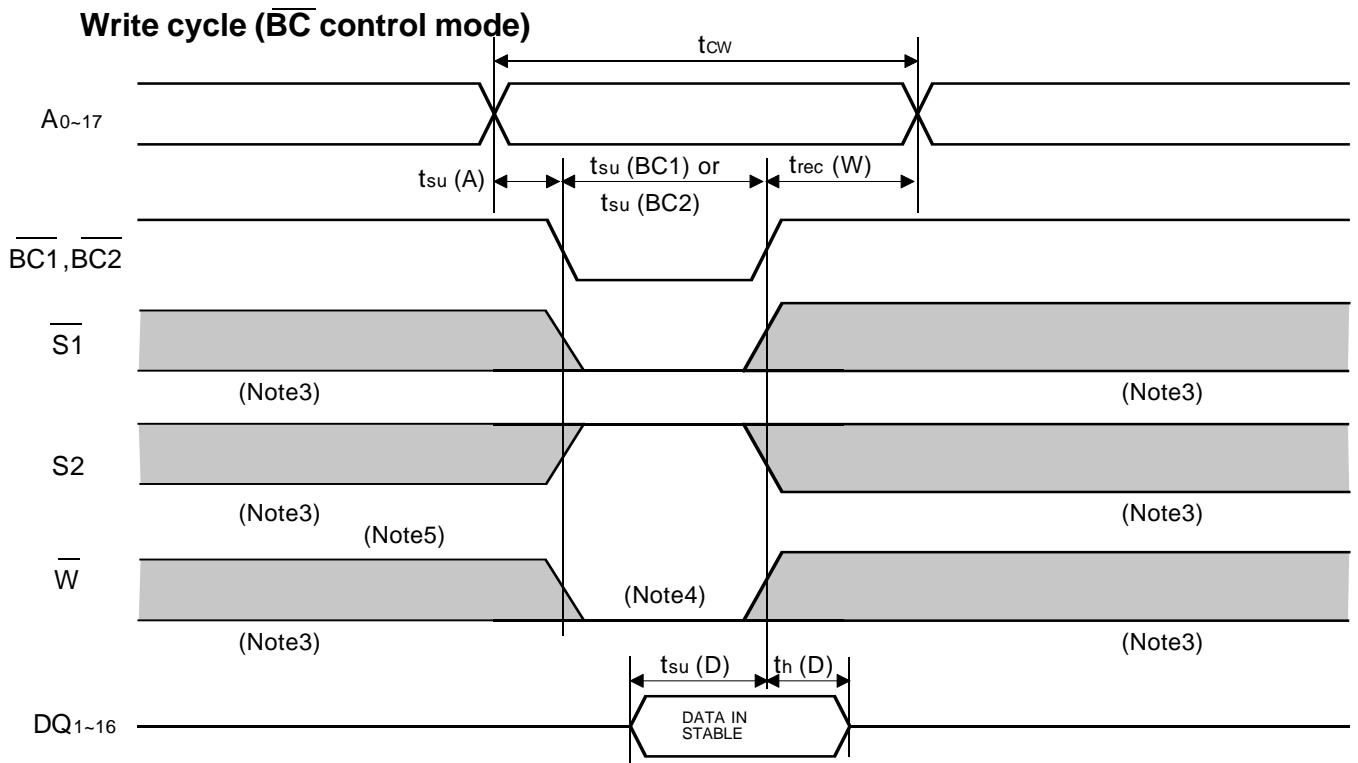
(2) READ CYCLE

Symbol	Parameter	Limits				Units	
		70L,70H,70LW 70HW,70LI,70HI		85L,85H,85LW 85HW,85LI,85HI			
		Min	Max	Min	Max		
t_{CR}	Read cycle time	70		85		ns	
$t_a(A)$	Address access time		70		85	ns	
$t_a(S1)$	Chip select 1 access time		70		85	ns	
$t_a(S2)$	Chip select 2 access time		70		85	ns	
$t_a(BC1)$	Byte control 1 access time		70		85	ns	
$t_a(BC2)$	Byte control 2 access time		70		85	ns	
$t_a(OE)$	Output enable access time		35		45	ns	
$t_{dis}(S1)$	Output disable time after S1 high		25		30	ns	
$t_{dis}(S2)$	Output disable time after S2 low		25		30	ns	
$t_{dis}(BC1)$	Output disable time after BC1 high		25		30	ns	
$t_{dis}(BC2)$	Output disable time after BC2 high		25		30	ns	
$t_{dis}(OE)$	Output disable time after OE high		25		30	ns	
$t_{en}(S1)$	Output enable time after S1 low	10		10		ns	
$t_{en}(S2)$	Output enable time after S2 high	10		10		ns	
$t_{en}(BC1)$	Output enable time after BC1 low	10		10		ns	
$t_{en}(BC2)$	Output enable time after BC2 low	10		10		ns	
$t_{en}(OE)$	Output enable time after OE low	5		5		ns	
$t_v(A)$	Data valid time after address	10		10		ns	

(3) WRITE CYCLE

Symbol	Parameter	Limits				Units	
		70L,70H,70LW 70HW,70LI,70HI		85L,85H,85LW 85HW,85LI,85HI			
		Min	Max	Min	Max		
t_{CW}	Write cycle time	70		85		ns	
$t_w(W)$	Write pulse width	55		60		ns	
$t_{su}(A)$	Address setup time	0		0		ns	
$t_{su}(A-WH)$	Address setup time with respect to \bar{W}	60		70		ns	
$t_{su}(BC1)$	Byte control 1 setup time	60		70		ns	
$t_{su}(BC2)$	Byte control 2 setup time	60		70		ns	
$t_{su}(S1)$	Chip select 1 setup time	60		70		ns	
$t_{su}(S2)$	Chip select 2 setup time	60		70		ns	
$t_{su}(D)$	Data setup time	35		35		ns	
$t_h(D)$	Data hold time	0		0		ns	
$t_{rec}(W)$	Write recovery time	0		0		ns	
$t_{dis}(W)$	Output disable time from \bar{W} low		25		30	ns	
$t_{dis}(OE)$	Output disable time from OE high		25		30	ns	
$t_{en}(W)$	Output enable time from \bar{W} high	5		5		ns	
$t_{en}(OE)$	Output enable time from OE low	5		5		ns	

M5M5V416BTP**4194304-BIT (262144-WORD BY 16-BIT) CMOS STATIC RAM****(4)TIMING DIAGRAMS****Read cycle****Write cycle (W control mode)**

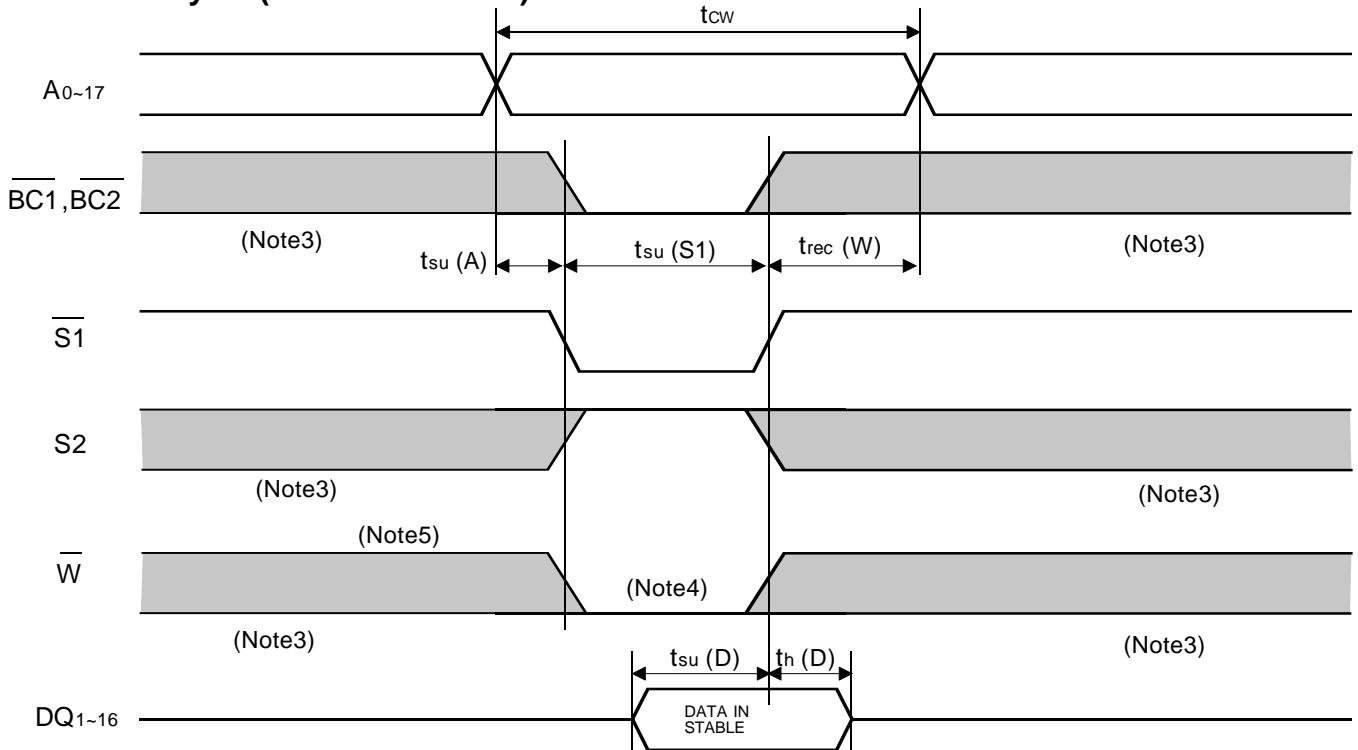
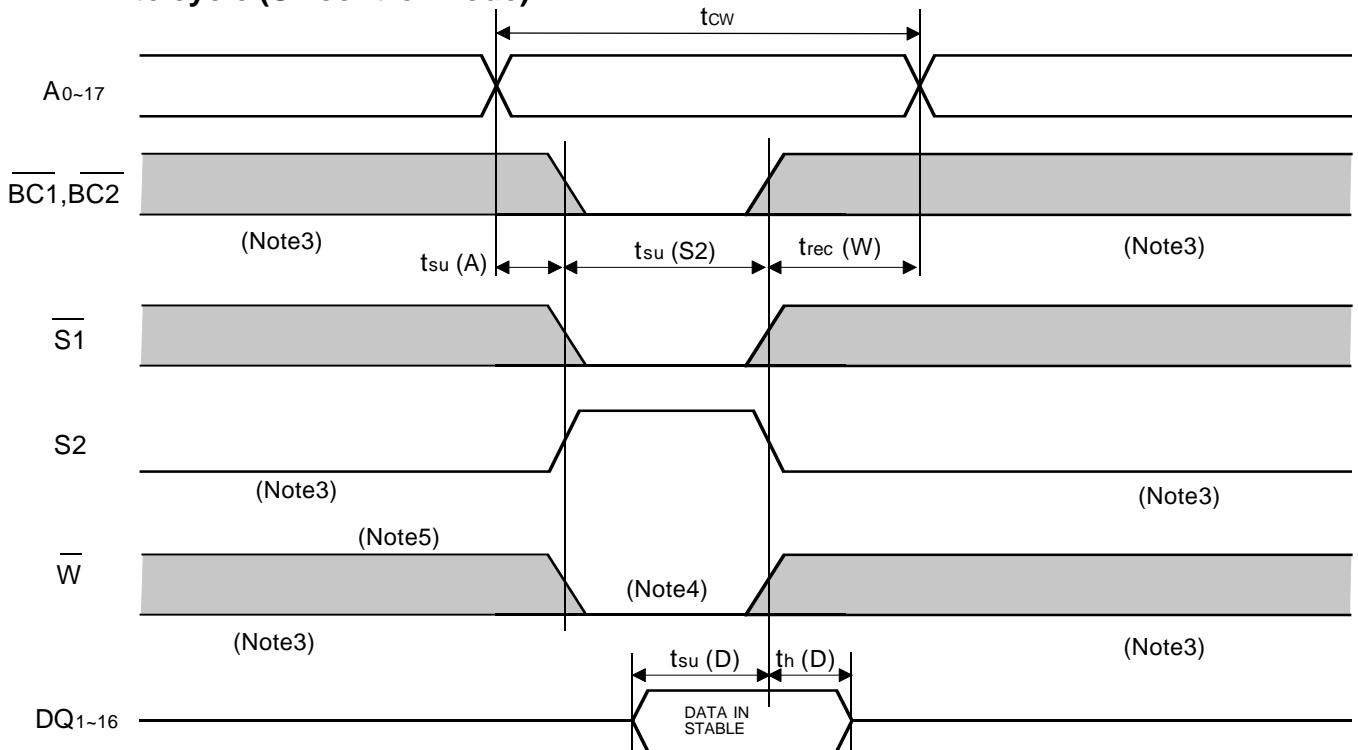
M5M5V416BTP**4194304-BIT (262144-WORD BY 16-BIT) CMOS STATIC RAM**

Note 3: Hatching indicates the state is "don't care".

Note 4: A Write occurs during S_1 low, S_2 high overlaps $\overline{BC1}$ and/or $\overline{BC2}$ low and \overline{W} low.

Note 5: When the falling edge of \overline{W} is simultaneously or prior to the falling edge of $\overline{BC1}$ and/or $\overline{BC2}$ or the falling edge of $\overline{S_1}$ or rising edge of S_2 , the outputs are maintained in the high impedance state.

Note 6: Don't apply inverted phase signal externally when DQ pin is in output mode.

M5M5V416BTP**4194304-BIT (262144-WORD BY 16-BIT) CMOS STATIC RAM****Write cycle (S1 control mode)****Write cycle (S2 control mode)**

M5M5V416BTP

4194304-BIT (262144-WORD BY 16-BIT) CMOS STATIC RAM

POWER DOWN CHARACTERISTICS

(1) ELECTRICAL CHARACTERISTICS

Symbol	Parameter	Test conditions	Limits			Units	
			Min	Typ	Max		
V _{CC} (PD)	Power down supply voltage		2.0			V	
V _I (BC)	Byte control input BC1 & BC2		2.0			V	
V _I (\bar{S}_1)	Chip select input \bar{S}_1		2.0			V	
V _I (S ₂)	Chip select input S ₂			0.2		V	
I _{CC} (PD)	Power down supply current	V _{CC} =3.0V <1> $S_1 \geq V_{CC} - 0.2V$ $S_2 \geq V_{CC} - 0.2V$ or $\leq 0.2V$ other inputs=0~3V <2> $S_2 \leq 0.2V$ other inputs=0~3V <3> \bar{BC}_1 and $\bar{BC}_2 \geq V_{CC} - 0.2V$ $S_1 \leq 0.2V$ or $S_2 \geq V_{CC} - 0.2V$ other inputs=0~3V	-LW, -LI -L, -LW, -LI -HW, -HI -H, -HW, -HI -H	+85°C +70°C +85°C +70°C 0 ~ +25°C -20 ~ +25°C -40 ~ +25°C	- - - - - 1 0.3 0.3 0.3	60 30 30 15 1 3 1 1	μA μA μA μA μA μA μA μA

(2) TIMING REQUIREMENTS

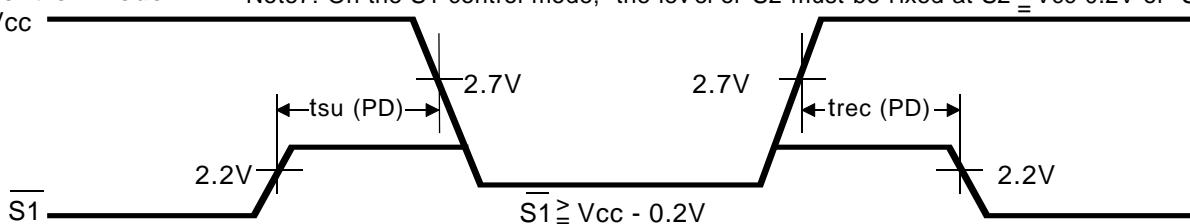
Typical value is for Ta=25°C

Symbol	Parameter	Test conditions	Limits			Units
			Min	Typ	Max	
t _{su} (PD)	Power down set up time		0			ns
t _{rec} (PD)	Power down recovery time		5			ms

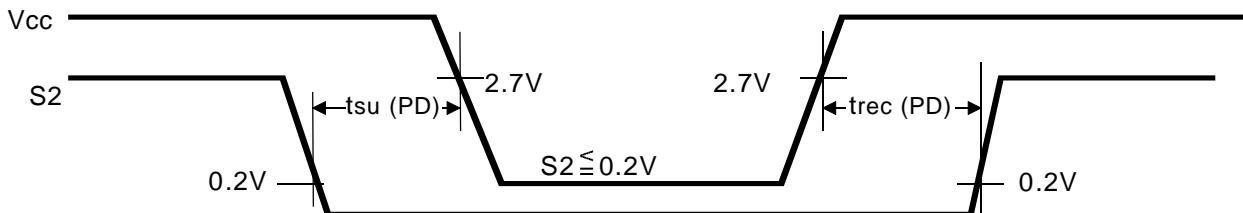
(3) TIMING DIAGRAM

S1 control mode

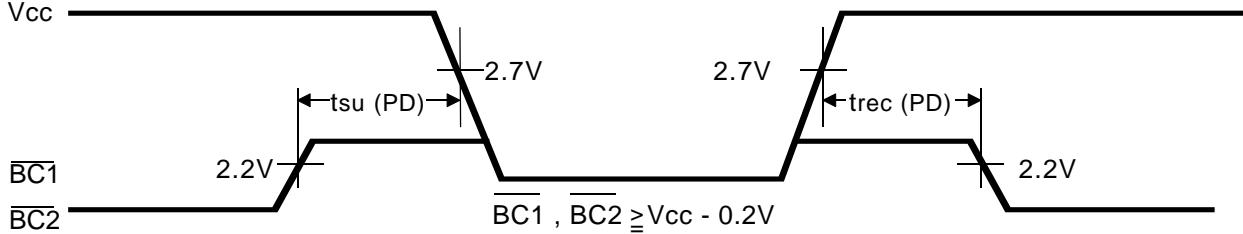
Note7: On the \bar{S}_1 control mode, the level of S₂ must be fixed at $S_2 \geq V_{CC} - 0.2V$ or $S_2 \leq 0.2V$.



S2 control mode



BC control mode



M5M5V416BTP

4194304-BIT (262144-WORD BY 16-BIT) CMOS STATIC RAM

Revision History

<u>Revision No.</u>	<u>History</u>	<u>Date</u>	<u>Remark</u>
P01	The first edition	'98 . 07 . 07	Preliminary
P02	Pin#28: NC --> S2	'98 . 07 . 14	Preliminary
P03	Font problem fixed	'98 . 08 . 27	Preliminary
P04	70ns version added	'98 . 12 . 16	Preliminary
P05	Icc1/Icc2 revised	'99 . 02 . 10	Preliminary
P06	1) Speed items revised: 100ns deleted 2) Icc3 and Icc(PD) limits revised	'99 . 03 . 10	Preliminary
P07	1) Errata corrected (page 8) 2) tsu(A-WH), tsu(BC1), tsu(BC2), tsu(S1) and tsu(S2) revised from 65ns to 60ns	'99 . 11 . 26	Preliminary
P10	The first product version	'00 . 06 . 01	-----



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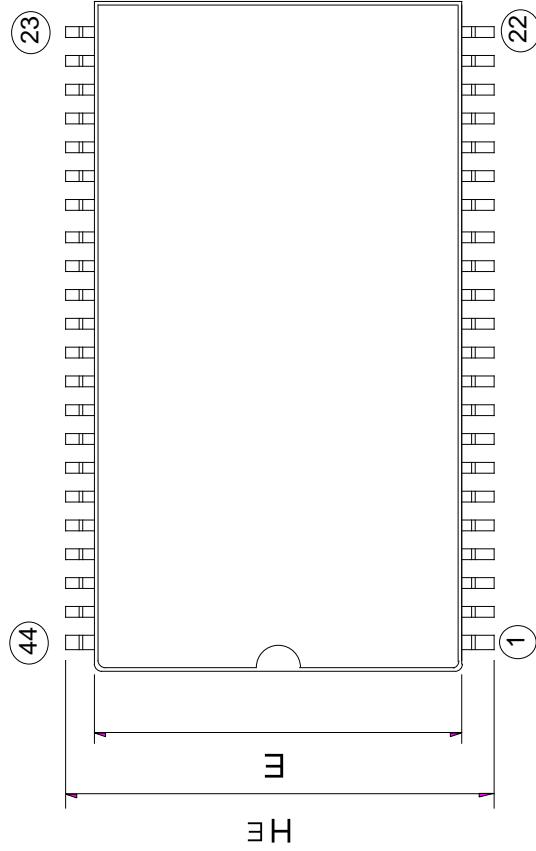
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44P3W-H

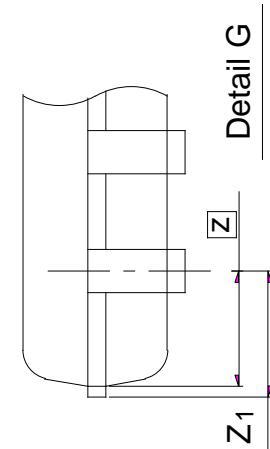
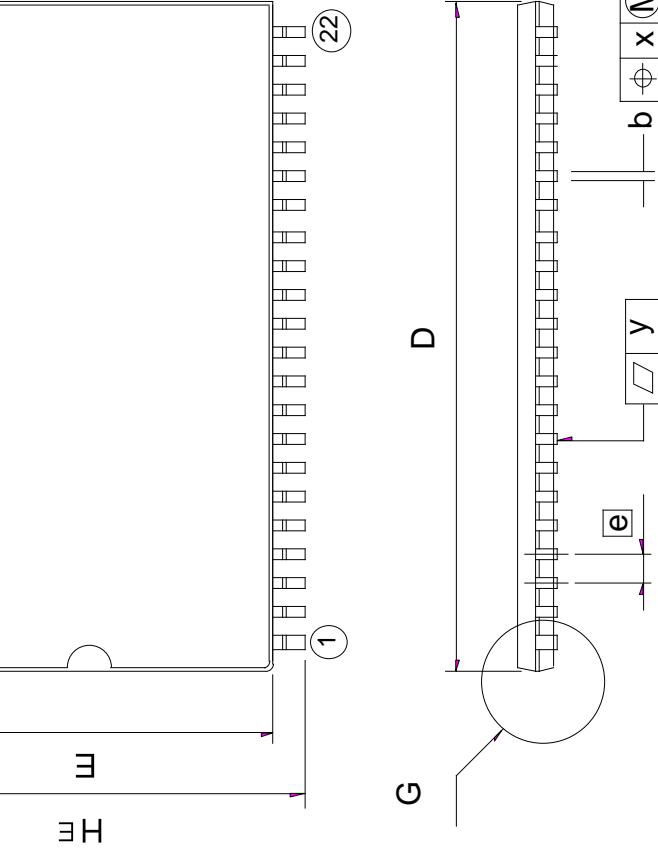
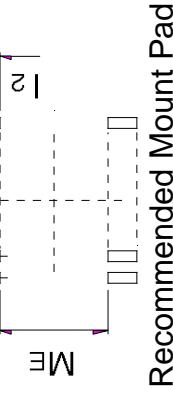
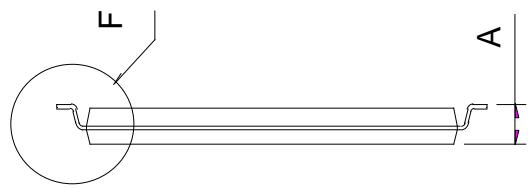
Plastic 44pin 400mil TSOP(II)

EIAJ Package Code	JEDEC Code	Weight(g)	Lead Material
TSOPII44-P-400-0.80	—	0.47	Alloy 42

Scale: 3/1



(44) (23) (22) (1)



Detail G

Recommended Mount Pad

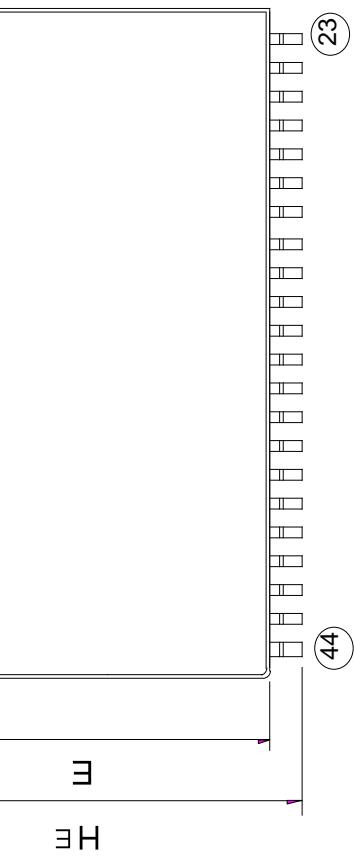
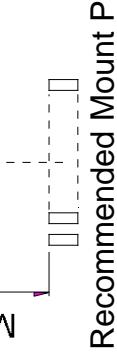
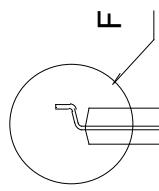
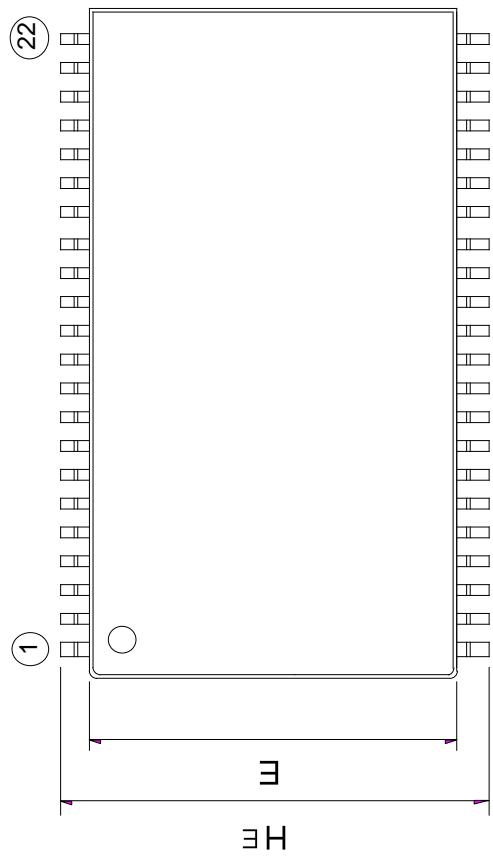
Symbol	Dimension in Millimeters		
	Min	Nom	Max
A	—	—	1.2
A ₁	0.05	0.125	0.2
A ₂	—	1.0	—
b	0.3	0.35	0.45
c	0.105	0.125	0.175
D	18.31	18.41	18.51
E	10.06	10.16	10.26
e	—	0.8	—
H _E	11.56	11.76	11.96
L	0.4	0.5	0.6
L ₁	—	0.8	—
L _P	0.45	0.6	0.75
A ₃	—	0.25	—
Z	—	0.805	—
Z ₁	—	—	0.955
X	—	—	0.16
Y	—	—	0.1
θ	0°	—	10°
M _E	—	10.36	—
I ₂	0.9	—	—
b ₂	—	0.5	—

44P3W-J

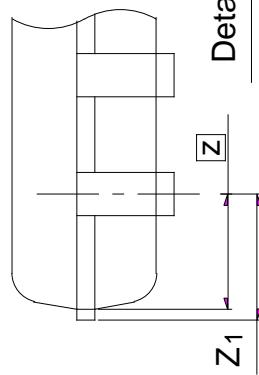
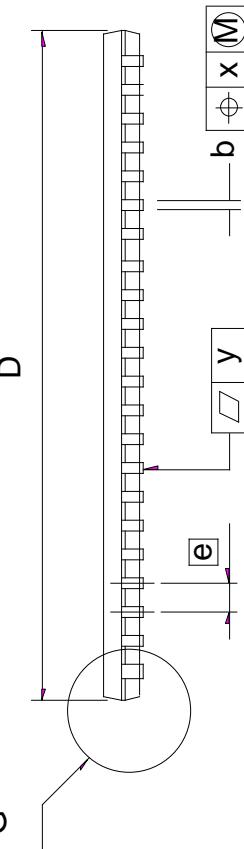
Plastic 44pin 400mil TSOP(II)

EIAJ Package Code	JEDEC Code	Weight(g)	Lead Material
TSOPII44-P-400-0.80	—	0.47	Alloy 42

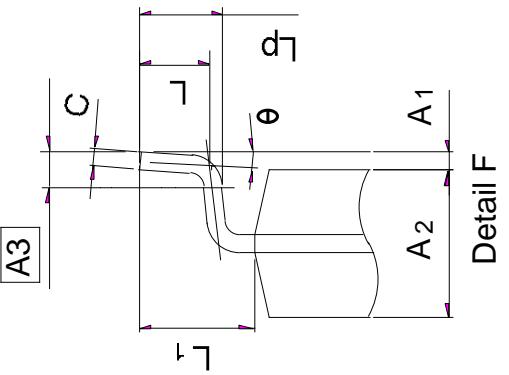
Scale: 3/1



D G



Z Detail G



Detail F

Recommended Mount Pad

Symbol	Dimension in Millimeters		
	Min	Nom	Max
A	—	—	1.2
A ₁	0.05	0.125	0.2
A ₂	—	1.0	—
b	0.3	0.35	0.45
c	0.105	0.125	0.175
D	18.31	18.41	18.51
E	10.06	10.16	10.26
e	—	0.8	—
HE	11.56	11.76	11.96
L	0.4	0.5	0.6
L ₁	—	0.8	—
Lp	0.45	0.6	0.75
A ₃	—	0.25	—
Z ₁	—	0.805	—
X	—	—	0.16
Y	—	—	0.1
θ	0°	—	10°
M _E	—	10.36	—
I ₂	0.9	—	—
b ₂	—	0.5	—